



APPLICATION DATA SHEET

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Title of Invention	INCREASE PRODUCTIVITY AT WAFER TEST USING PROBE RETEST DATA ANALYSIS		
Application Type : regular, utility Attorney Docket Number : BUR920040137US1			
Correspondence address: Customer Number: 29154			
			
Inventor Information: <u>Inventor 1:</u> Applicant Authority Type: Inventor Citizenship: US Given Name: Akiko Middle Name: F. Family Name: Balchiunas Residence: City of Residence: Hinesburg State of Residence: VT Country of Residence: US Address-1 of Mailing Address: 401 Butternut Lane Address-2 of Mailing Address: City of Mailing Address: Hinesburg State of Mailing Address: VT Postal Code of Mailing Address: 05461 Country of Mailing Address: US Phone: Fax: E-mail:			
Attorney Information: practitioner(s) at Customer Number: 29154			
 as my attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.			

Assignee 1:

Organization Name:	International Business Machines Corporation
Address-1 of Mailing Address:	New Orchard Road
Address-2 of Mailing Address:	
City of Mailing Address:	Armonk
State of Mailing Address:	NY
Postal Code of Mailing Address:	10504
Country of Mailing Address:	US
Phone:	
Fax:	
E-mail:	